

# Finite element techniques for modeling the effect on circuit board dynamic response of mechanical coupling at electrical board-to-board connectors

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# Presentation Outline

- Design of electronics packaging
- Case study
- Literature
- Experimental test setup
- Preliminary FE analyses
- Comparison of results
- Preliminary conclusions
- Proposed future work
- Questions



# Presentation Outline

- Design of electronics packaging
- Case study
  - Analysis of single circuit board design
  - Research motivation: designs with multiple circuit boards
- Literature
- Experimental test setup
- Preliminary FE analyses
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# Electronics packaging designs

- Typical requirements

- Volume constraint
- Interface
  - Mounting features
  - Electrical connectors

- Circuit board area

- Mass properties

- Weight, c.g.
- Inertia tensor

- Design-for

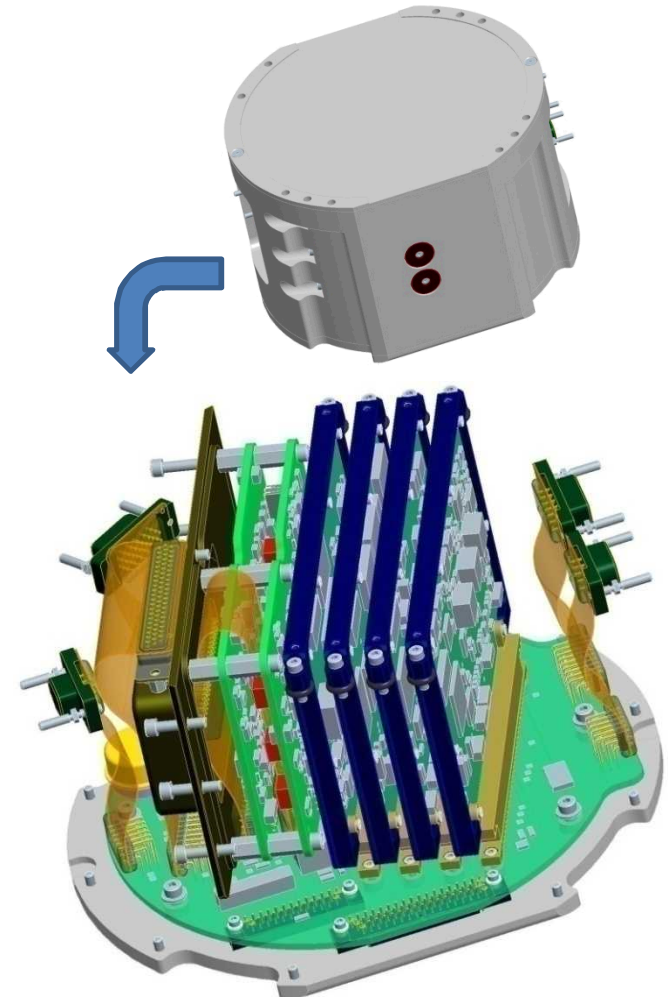
- Manufacture
- (Dis-)Assembly
- Environment

- Ruggedness

- Vibration, shock
- Thermal

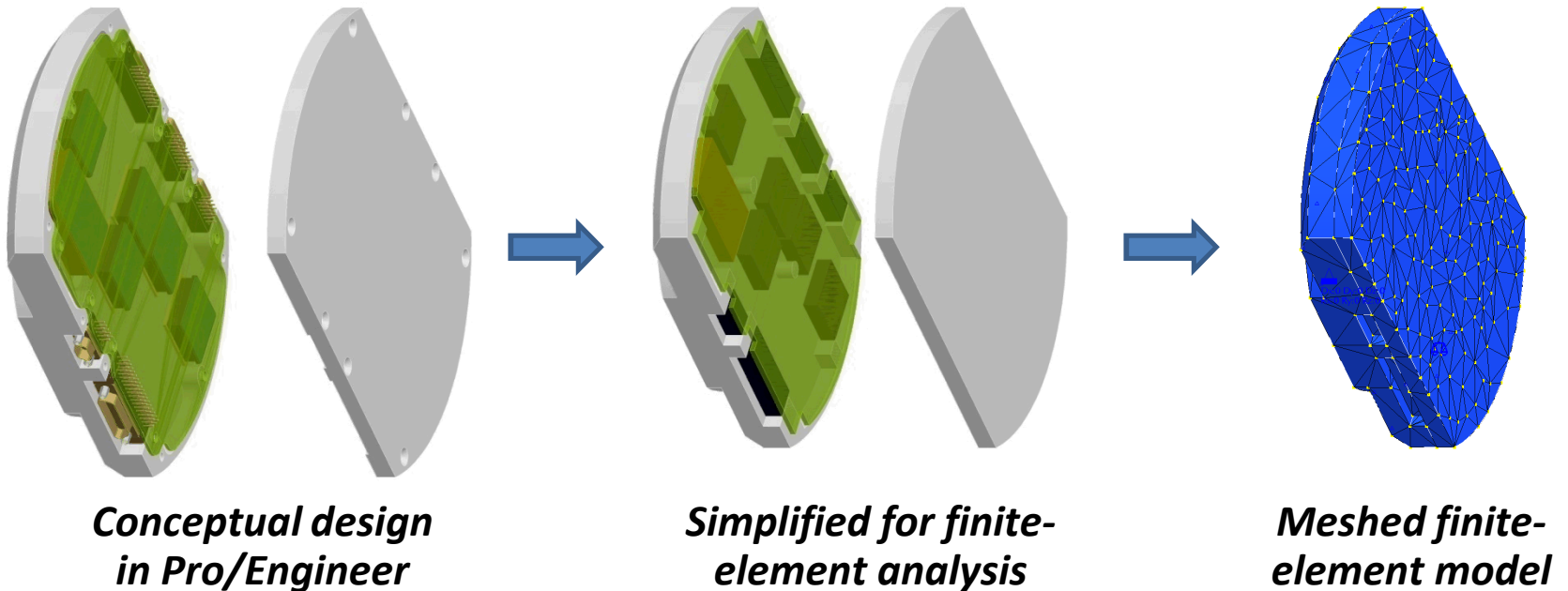
*Trade space:*

- *size, geometry*
- *quantity*
- *interconnect scheme*
- *mounting method*



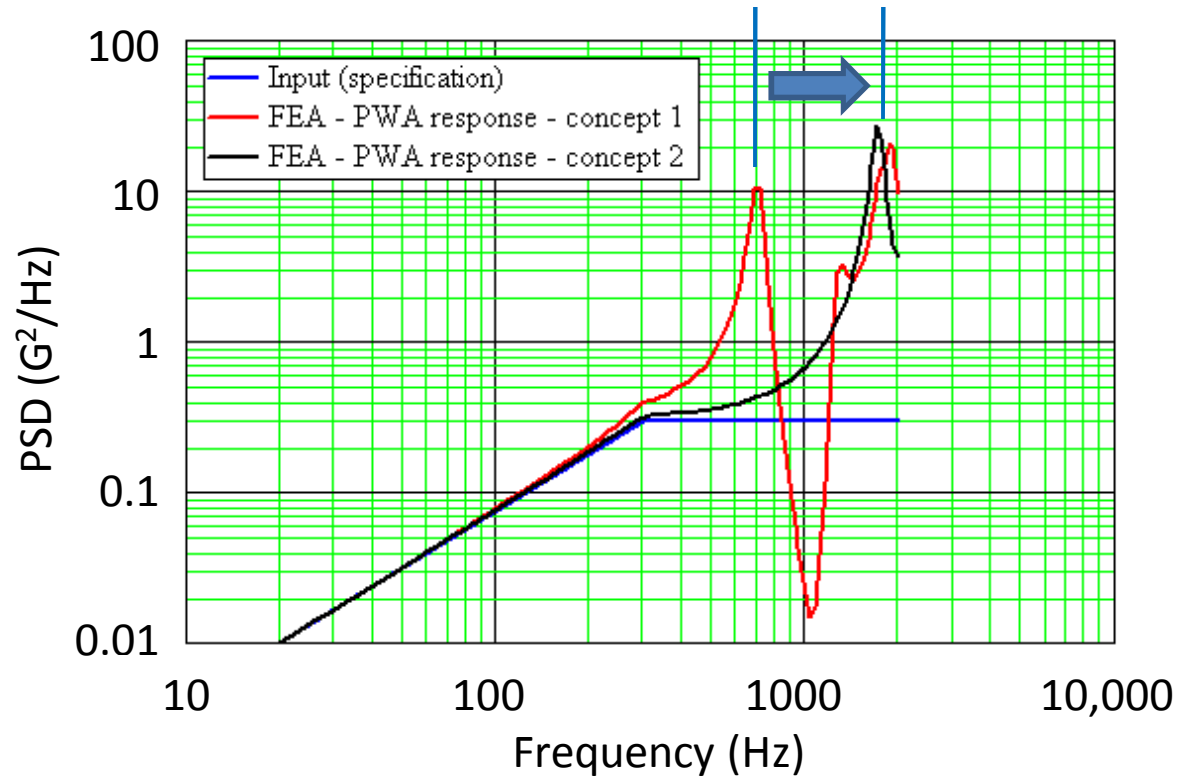
# Case study: single circuit board design

- Early design concept



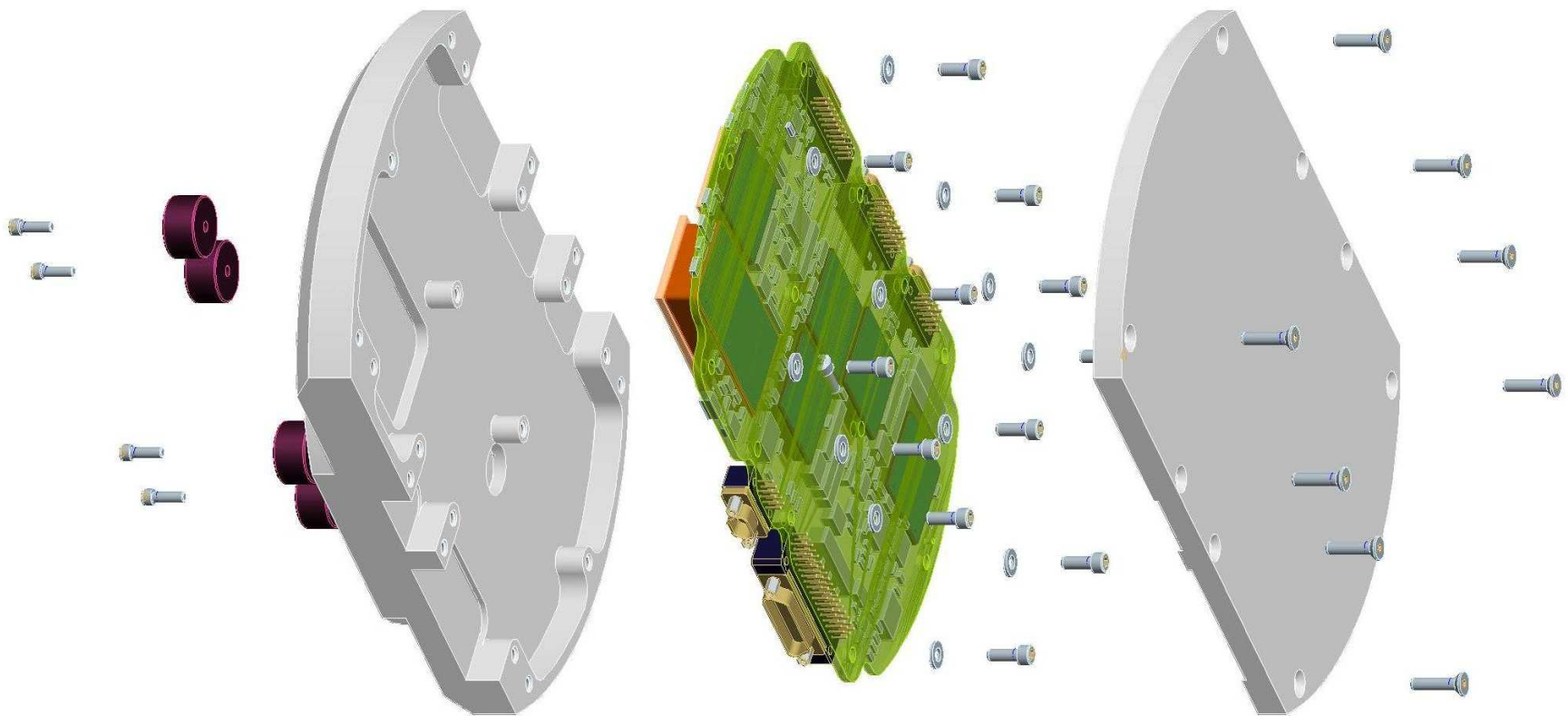
# Case study: single circuit board design

- Early analysis of design concept in vibration environment
  - Circuit board material properties from literature
  - Result: desire to increase 1<sup>st</sup> natural frequency
  - Modify design concept based on result



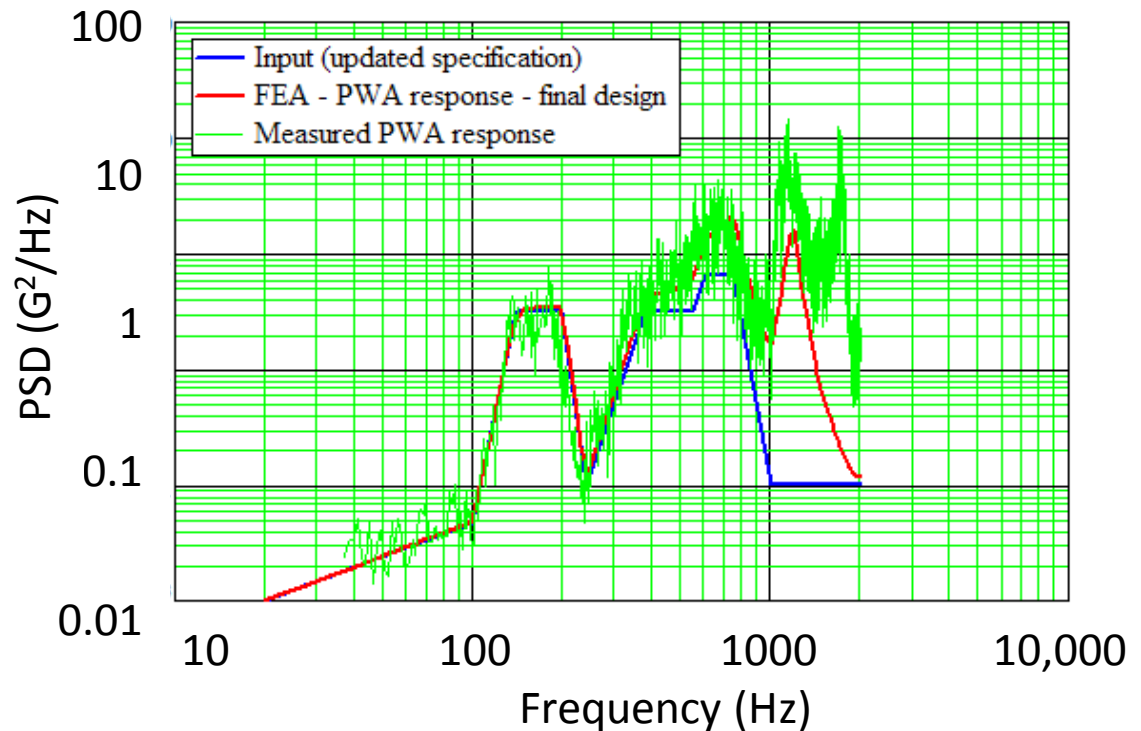
# Case study: single circuit board design

- Final design

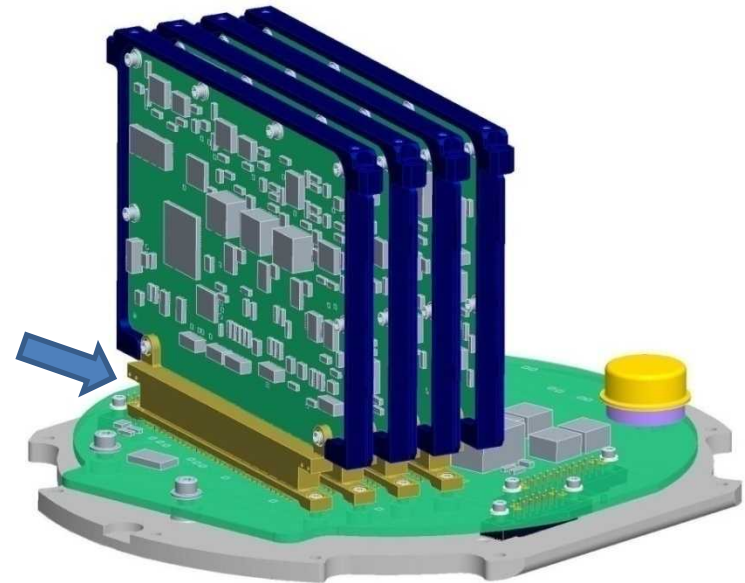
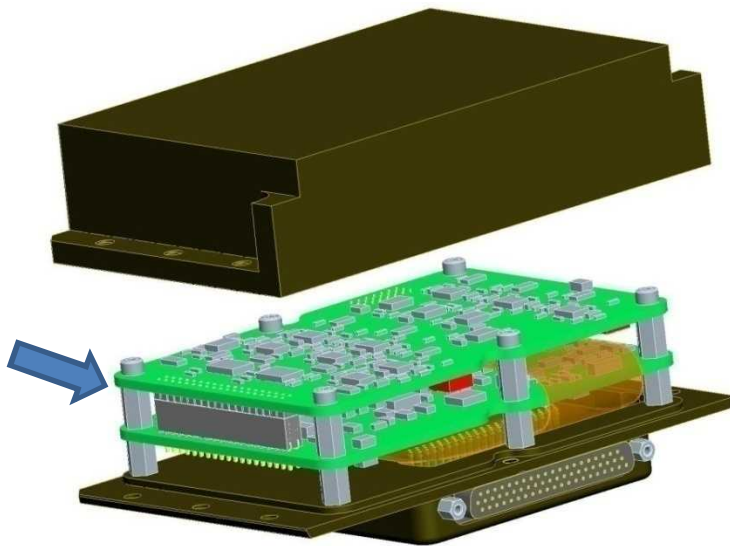


# Case study: single circuit board design

- Repeat analysis for final design
  - Updated environmental specification
  - Circuit board material properties from literature
  - Good agreement with laboratory results



# Multiple circuit board designs



- Circuit board response affected by mechanical coupling at electrical board-to-board connectors
- Research goals
  - Characterize this effect and develop modeling techniques
  - Enable efficient FEA modeling for conceptual design studies



# Literature

## ***FEA of individual circuit boards in vibration and shock***

- *Park et al. (2007)<sup>1</sup>*
- *Pitarresi et al. (2004)<sup>2</sup>*
- *Wu et al. (2002)<sup>3</sup>*

## ***Simplified FEA models for optimizing conceptual designs in vibration***

- *Donders et al. (2009)<sup>5</sup>*
- *Mundo et al. (2009)<sup>6</sup>*
- *Pitarresi et al. (2004)<sup>2</sup>*

*FEA techniques for mechanical coupling at electrical board-to-board connectors*

## ***FEA methods for circuit board boundary conditions in vibration and shock***

- *Lee et al. (2008)<sup>4</sup>*
- *Park et al. (2007)<sup>1</sup>*

## ***Electrical connector fretting due to vibration***

- *Flowers et al. (2004)<sup>7</sup>*
- *Van Dijk et al. (1996)<sup>8</sup>*

- Effect on circuit board response is not well-characterized in literature

- Suitable finite-element modeling techniques are not presented in literature

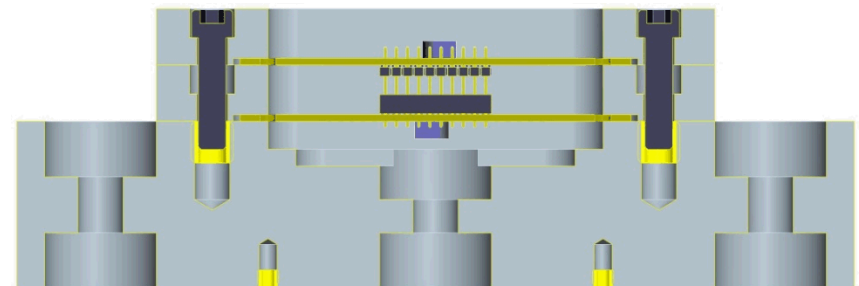
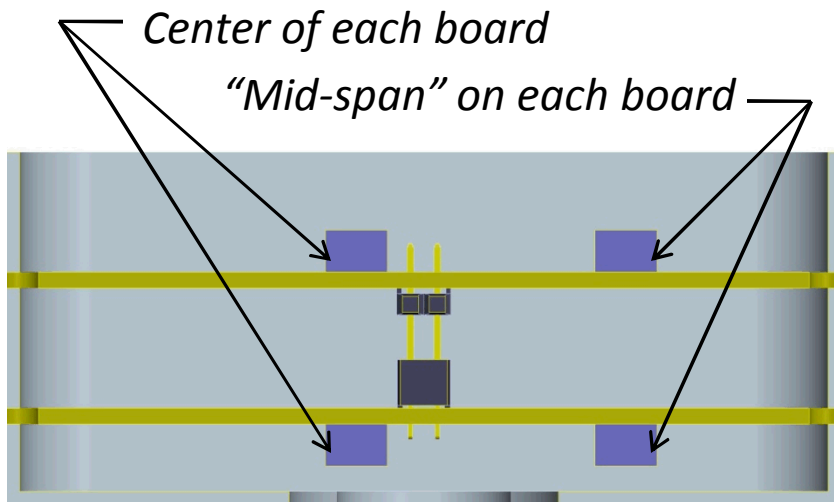
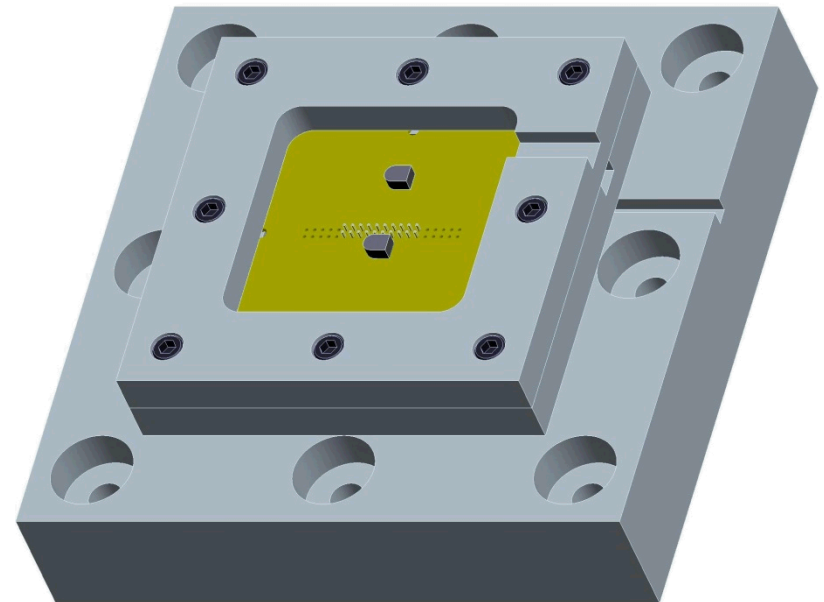


# Presentation Outline

- Design of electronics packaging
- Case study
- Literature
- **Experimental test setup**
  - Goal: collect response data using 2 circuit boards with connector for FE model validation
- Preliminary FE analyses
- Comparison of results
- Preliminary conclusions
- Proposed future work
- Questions

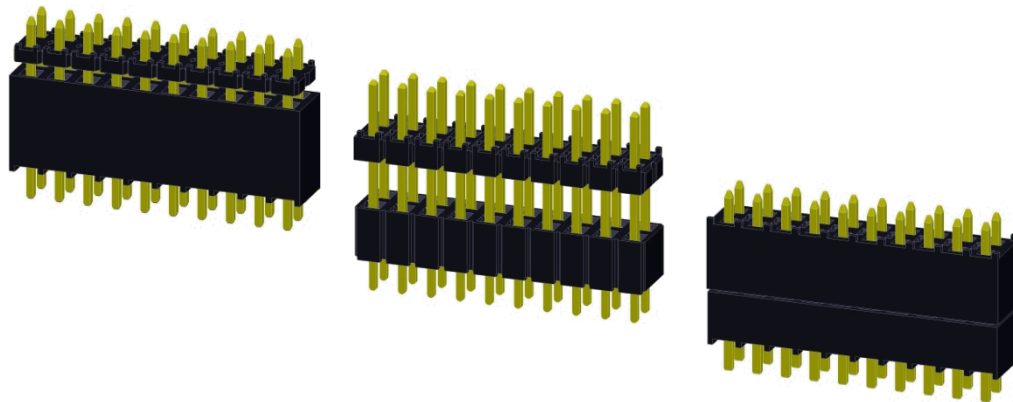
# Overview of test setup

- 2 circuit boards
  - 3.5 inches square, 1/16<sup>th</sup> inch thick
  - FR4 Tg 140 epoxy laminate
  - Electrical connector located at center of boards
- Response measured using 4 uni-axial accelerometers



# Electrical connectors: 9 types

- 3 unique styles
  - Engagement/pull-out force
  - Bending stiffness
  - Mass
- 3 sizes of each style
  - 20, 30, and 40 pin



**Samtec**  
IPT1, IPS1 SERIES

**SHROUDED POWER CONNECTOR SET**

**SPECIFICATIONS**  
For complete specifications, see www.samtec.com/IPT1 or www.samtec.com/IPS1  
Insulator Material: Black LCP  
Contact Material: Phosphor Bronze  
Plating: Sn or Au over 50µ" (1.27µm) Ni  
Operating Temp Range: -55°C to +125°C with 100% humidity  
Insertion Depth: (2.7mm) 0.106"  
140° to (0.49mm) 0.019"  
Wiring Distance: (0.39mm) 0.015"  
Insertion Force (SMT): 3.0oz (0.89N) avg  
Withhold Force (SMT): 2.6oz (0.72N) avg  
Insertion Force (THT): 6.0oz (1.67N) avg  
Withhold Force (THT): 5.0oz (1.38N) avg  
Voltage Rating: 550 VAC  
RoHS Compliant: Yes

CURRENT RATING	
AMBIENT TEMP	IPT1/IPS1
20°C	8A
40°C	7.2A
60°C	6A
95°C	4.1A

6 POSITIONS (2x3)

**APPLICATION SPECIFIC OPTION**  
Latching feature available. Call Samtec.

**APPLICATION**  
IPT1

**Processing:**  
Max Processing Temp: 230°C for 60 seconds, or 250°C for 20 seconds, or  
SMT Lead Coplanarity: (0.13mm) 0.005" max (0.5-10) (0.15mm) 0.006" max (15-25)  
Note: Other Gold plating options available. Contact Samtec.  
Note: Some sizes, styles and options are non-standard, non-returnable.

**Options:**  
IPT1: 1 NO. PINS PER ROW  
LEAD STYLE: 01, 05, 10, 15, 20, 25 (Call Samtec for other sizes)  
PLATING OPTION: -L (10µ" (0.25µm) Gold on contact, Matte Tin on Tail)  
TAIL OPTION: -D (Requires -01 Lead Style (Leave blank for Through-Hole))  
OTHER OPTION: -K (±0.00mm) 230° DIA Polyimide film Pick & Place Pad (-VS only), -LC (Locking Clip (-VS only) (N/A with -A)), -A (Alignment Pin (-VS only) (N/A with -LC)), -POL (No. 1 position polarized)

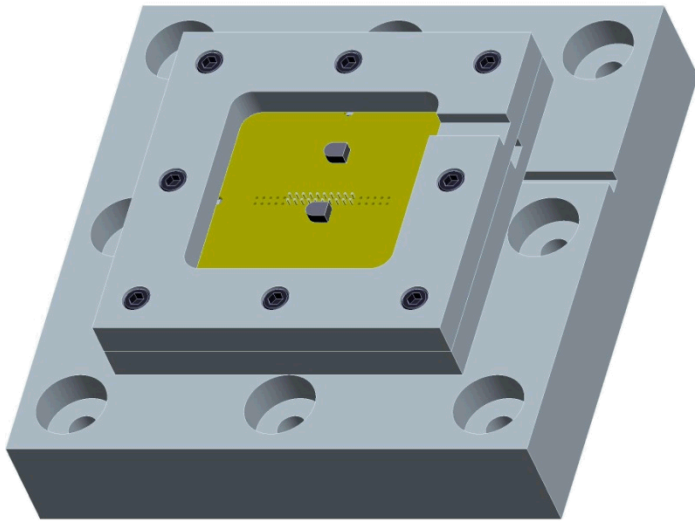
**Options:**  
IPS1: 1 NO. PINS PER ROW  
LEAD STYLE: 01, 05, 10, 15, 20, 25 (Call Samtec for other sizes)  
PLATING OPTION: -L (10µ" (0.25µm) Gold on contact, Matte Tin on Tail)  
TAIL OPTION: -D (Leave blank for Through-Hole)  
OTHER OPTION: -K (±0.00mm) 230° DIA Polyimide film Pick & Place Pad (-VS only), -LC (Locking Clip (-VS only) (N/A with -A)), -A (Alignment Pin (-VS only) (N/A with -LC)), -POL (No. 1 position polarized), -TR (Tape & Reel Packaging)

**BUY CONTACT**

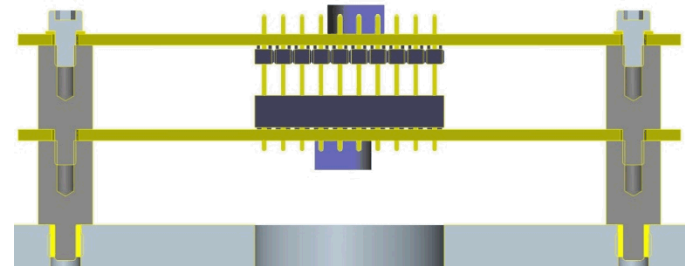
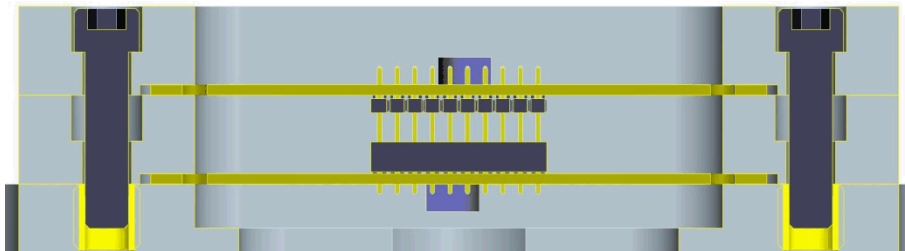
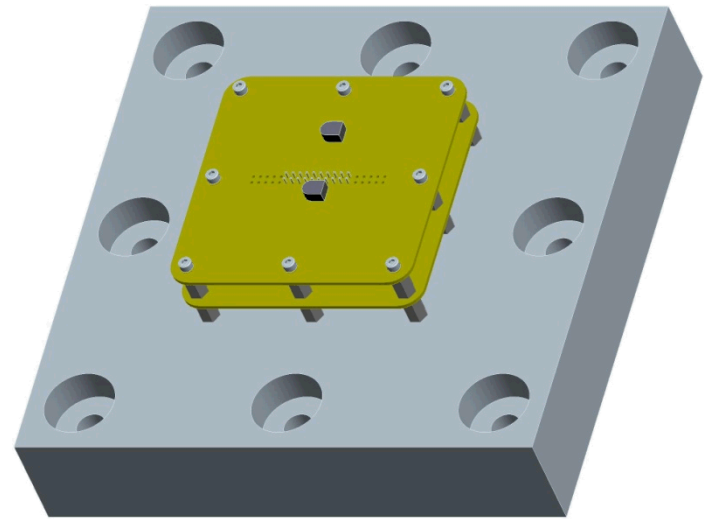


# Edge constraint: 2 types

*Clamp rings*

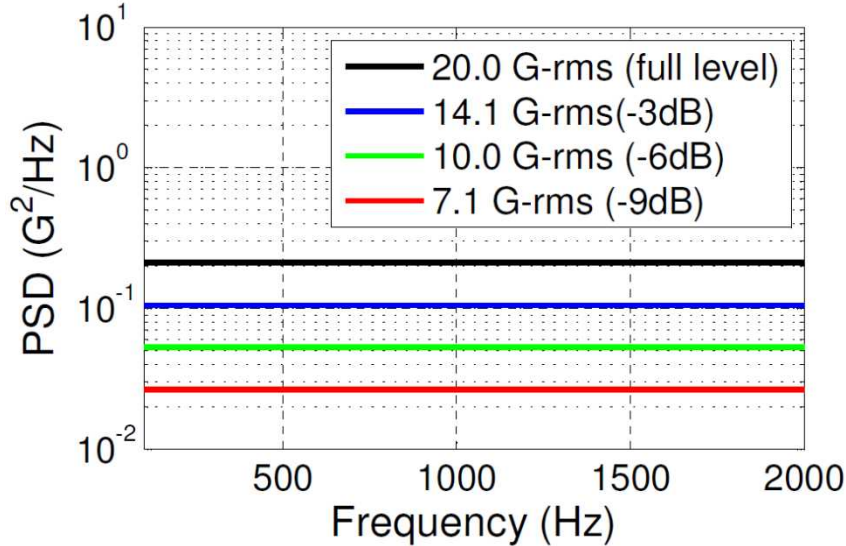


*Hex standoffs & fasteners*

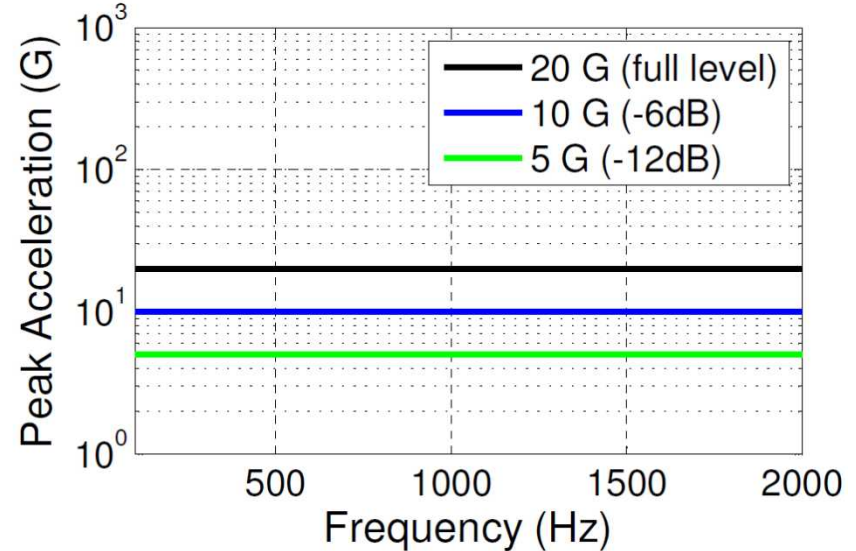


# Dynamic loading

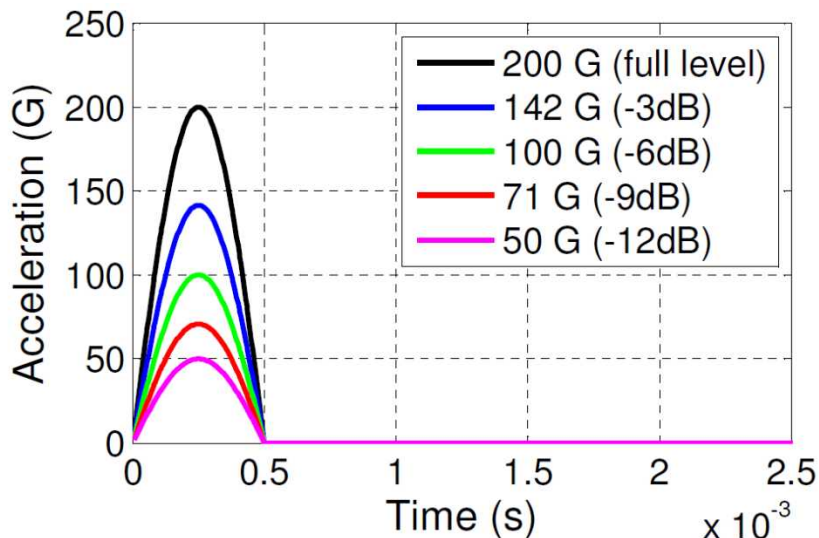
**Random vibration – flat spectrum**



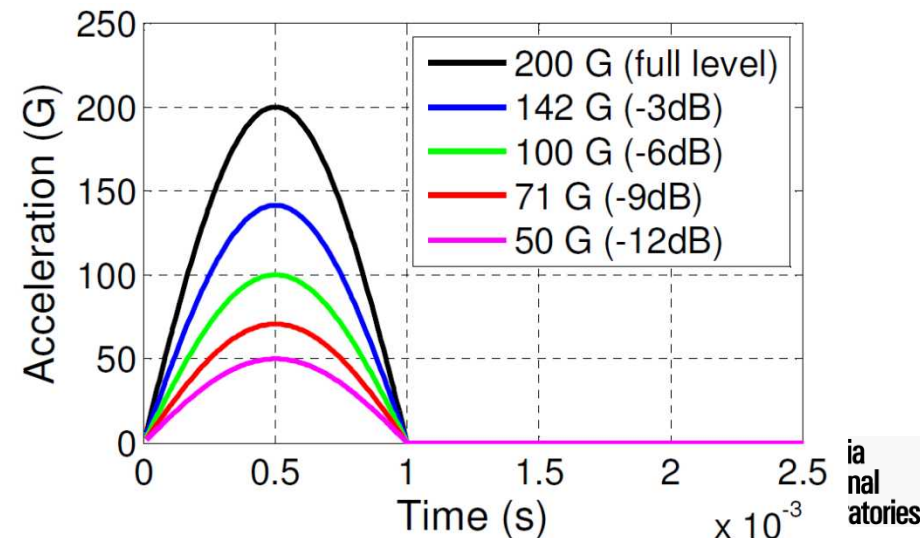
**Sinusoidal vibration – frequency sweep**



**0.5 ms half-sine shock**



**1.0 ms half-sine shock**





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- Experimental test setup
- Preliminary FE analyses
  - Goal: predict response with ‘bounding’ estimates of 1<sup>st</sup> natural frequency
- Comparison of results
- Preliminary conclusions
- Proposed future work
- Questions



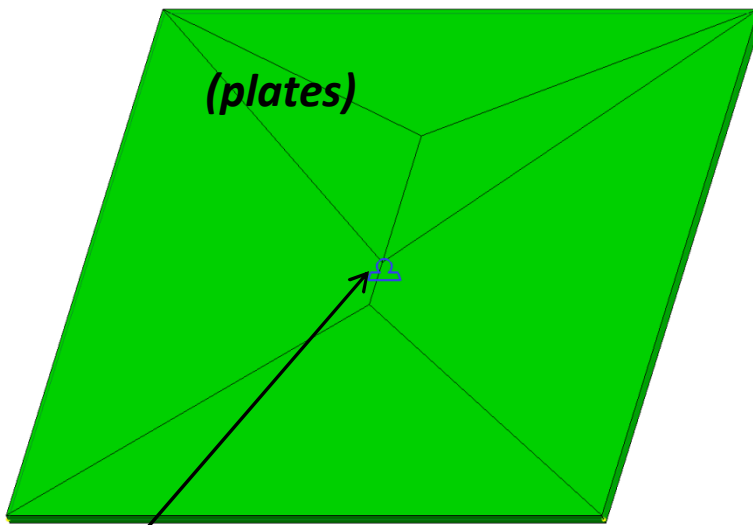
# Preliminary FE analyses

- Software
  - Mechanics (Pro/Engineer)
  - P-element code
  - Semi-automated meshing
- Model parameters
  - Estimates for FR4 material properties (from literature)
  - Estimate 5% damping
- Typical model size
  - No. elements:
  - No. nodes:
  - Run time: 1 to 45 minutes

Parameter	Details
Connector size & style	Mass
	Stiffness
	Size
Edge constraint type	Clamped
	Standoffs
Dynamic loading type & level	Random vibration
	Swept sine
	Half-shock

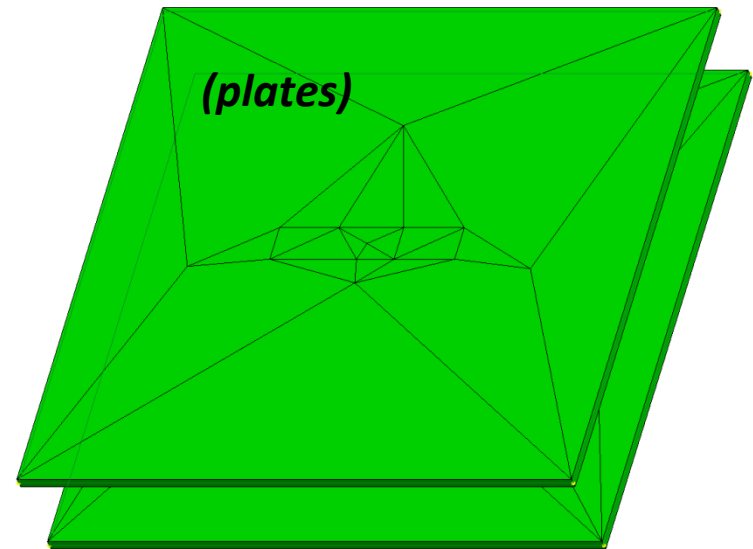
# Preliminary models: clamped

*Lower bound: "Compliant" model  
(ignores connector)*



**Connector  
(point mass)**

*Upper bound: "Rigid" model  
(connector stiffness =  $10 \times 10^6$  psi)*



**Connector (tetrahedrals)**

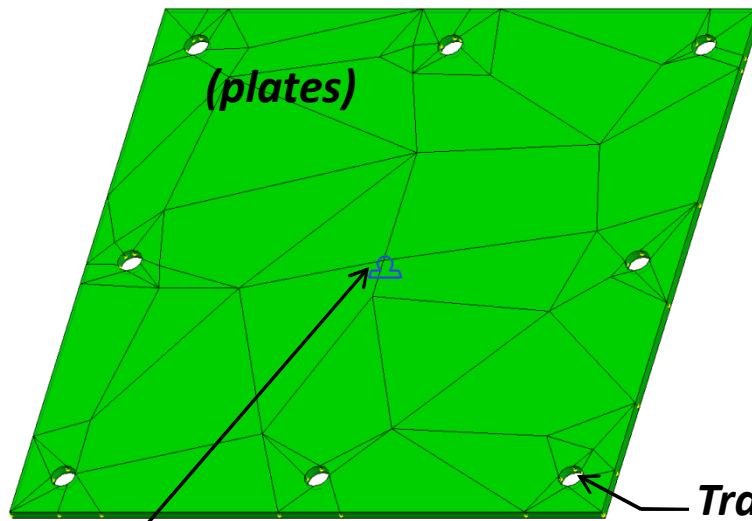
**NOTE:  
P-element  
code!**

**6 DOFs fixed  
along edges**

# Preliminary models: standoffs

*Lower bound: "Compliant" model  
(ignores connector)*

*Upper bound: "Rigid" model  
(connector stiffness =  $10 \times 10^6$  psi)*

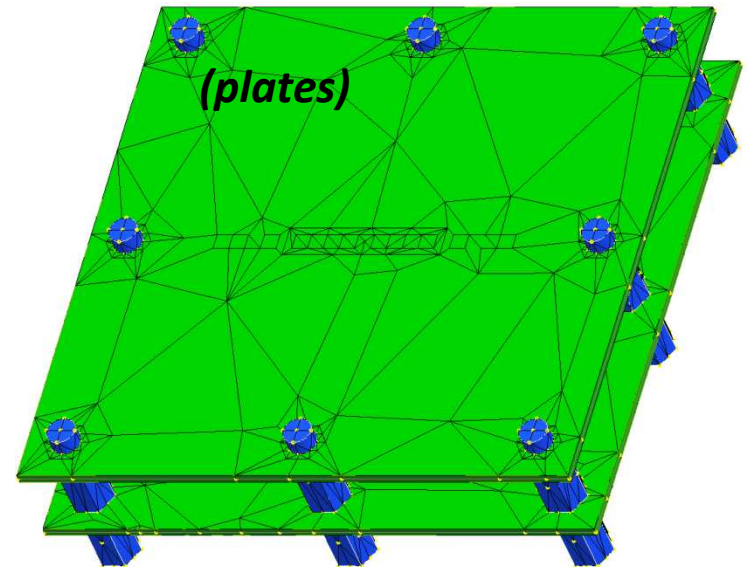


**(plates)**

**NOTE:**  
**P-element**  
**code!**

**Translation**  
**fixed at holes**

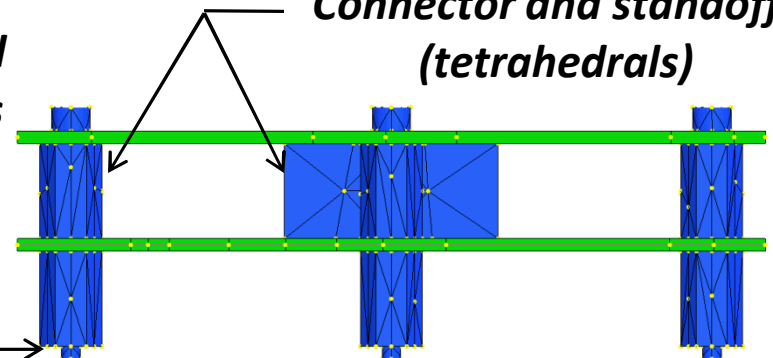
**Connector**  
**(point mass)**



**(plates)**

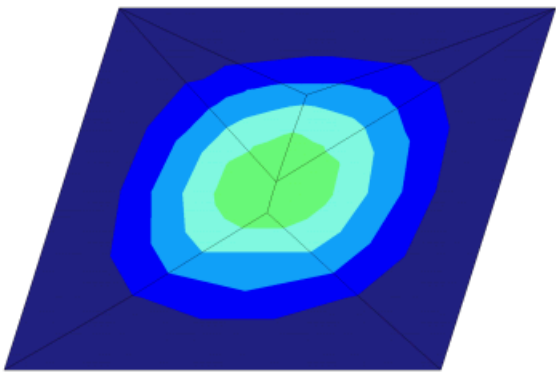
**Connector and standoffs**  
**(tetrahedrals)**

**6 DOFs fixed**  
**at standoffs**

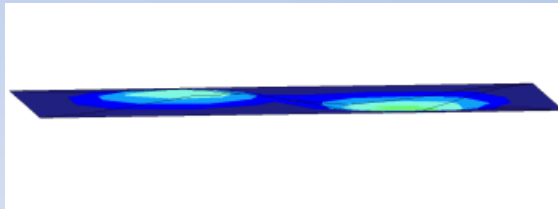


# Mode shapes

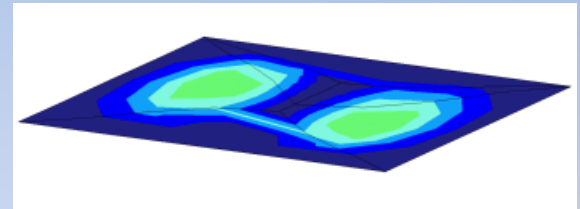
*Bound 1: No mechanical coupling*



*Mode 1*

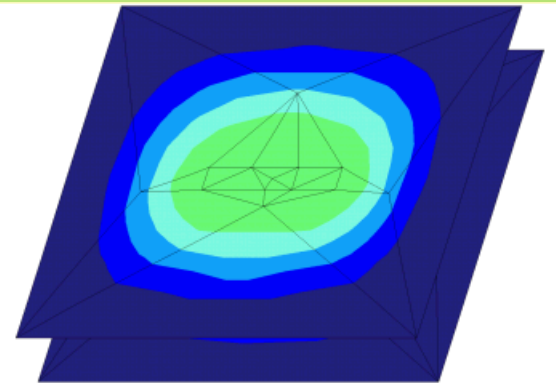


*Mode 2*

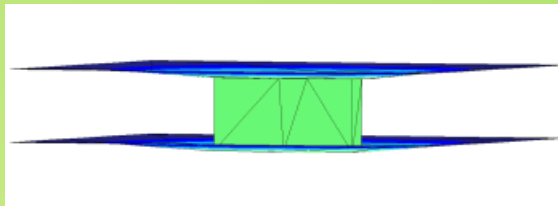


*Mode 3*

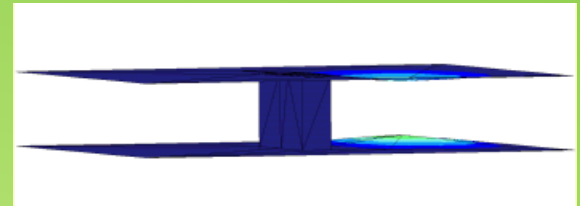
*Bound 2: Rigid mechanical coupling*



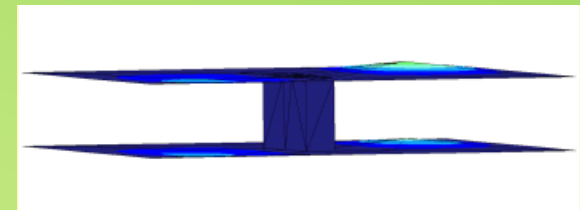
*Mode 1*



*Mode 1 (side view)*



*Mode 2*



*Mode 3*



# Modal frequencies

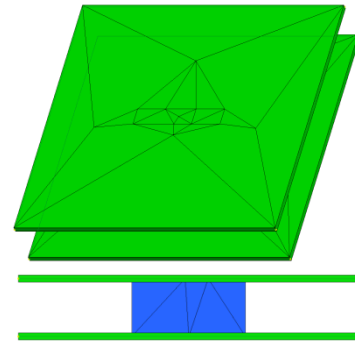
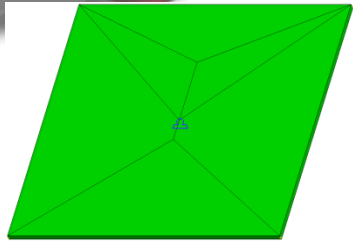
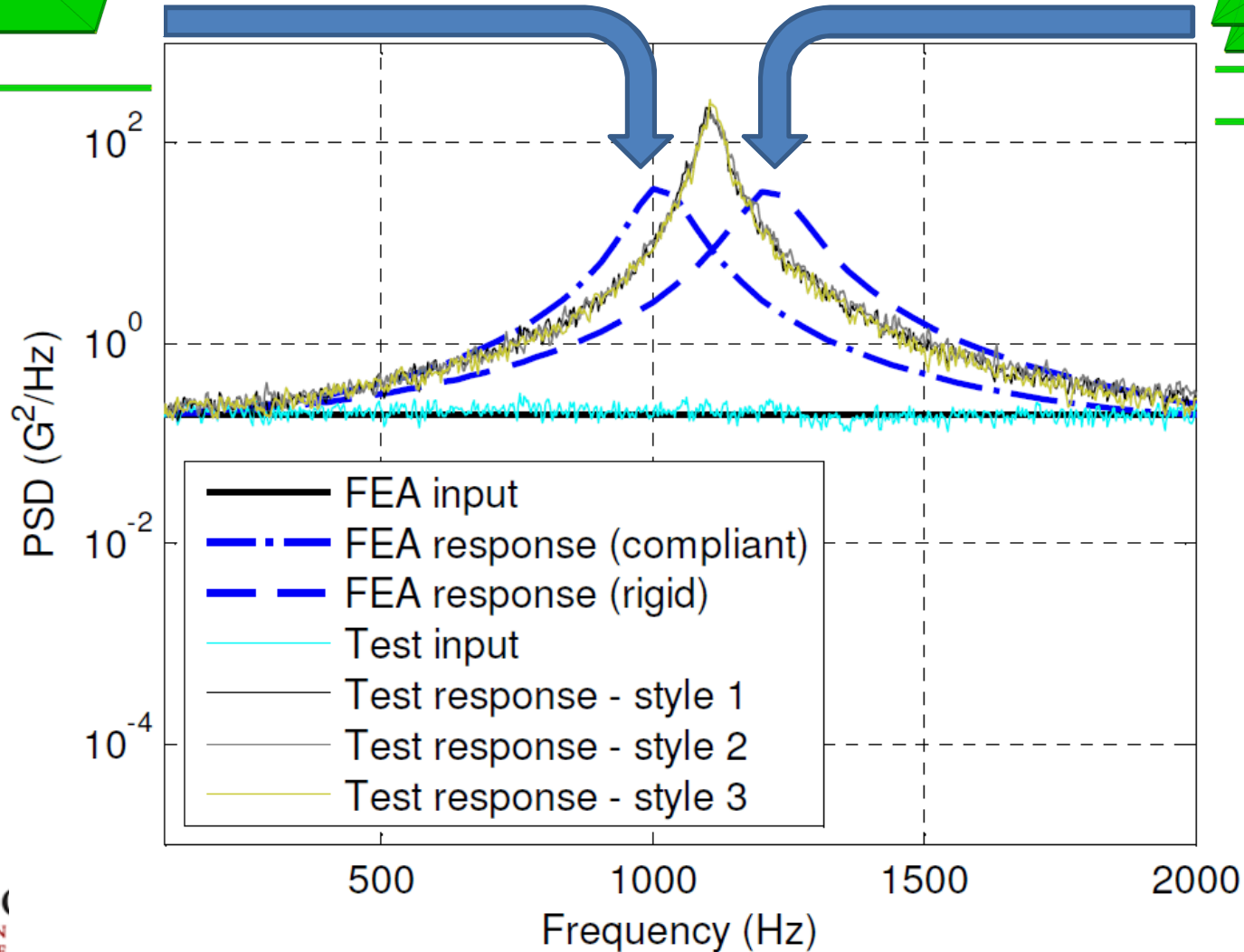
Boundary condition	No. pins	Mechanical coupling	Mode		
			1 <sup>st</sup>	2 <sup>nd</sup>	3 <sup>rd</sup>
Clamped	20	None	1015	2483	2725
		Rigid	1217	3312	3443
	40	None	878	2477	2719
		Rigid	1845	3341	3497
Standoffs	20	None	810	1771	1849
		Rigid	1142	2754	2785
	40	None	718	1771	1849
		Rigid	1737	2910	2961



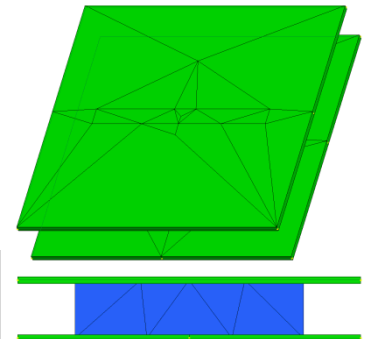
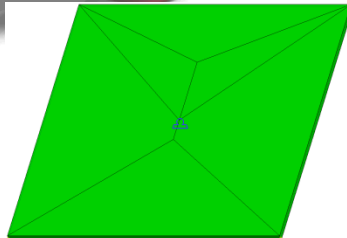
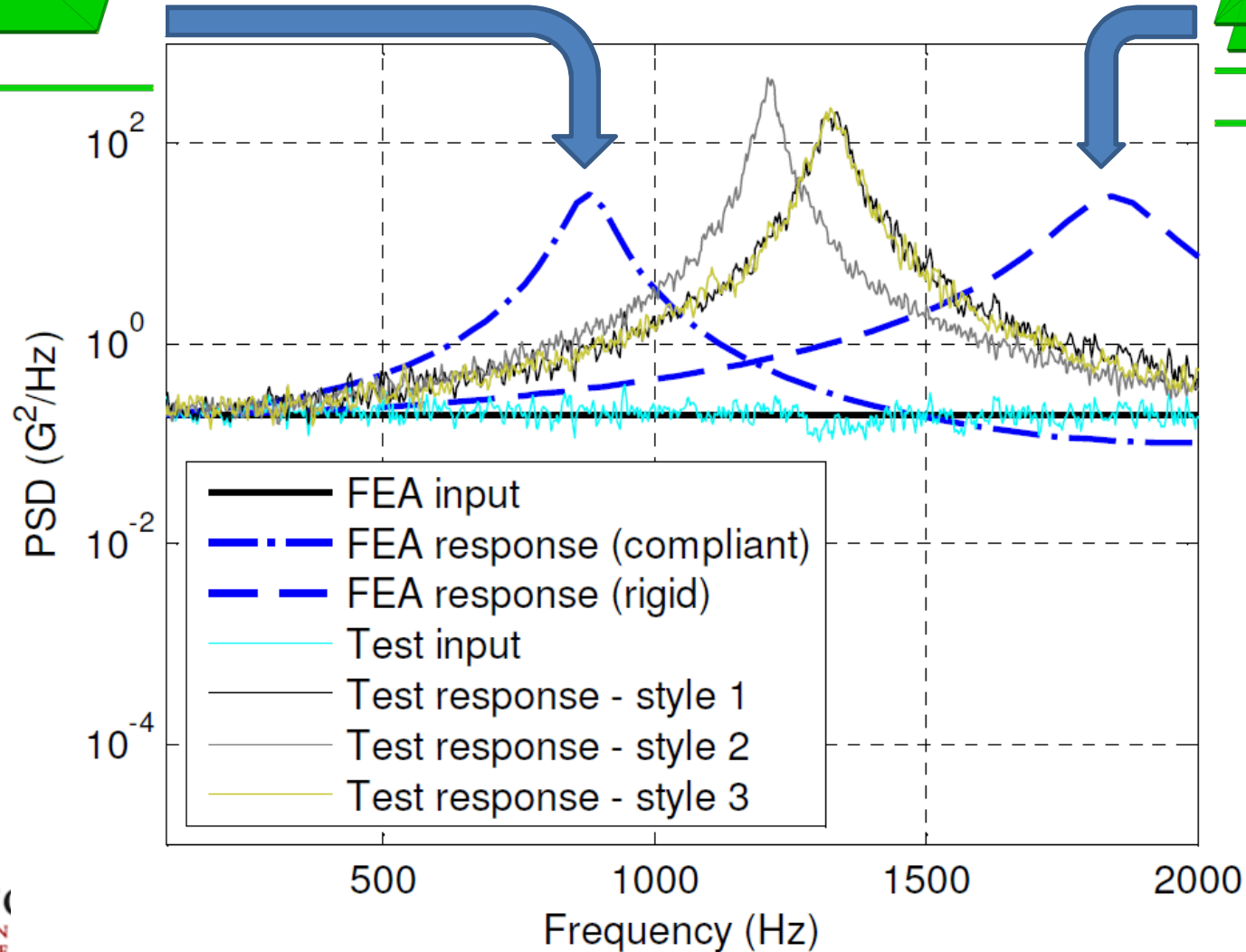
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# Clamped, 20 pin, top board, center



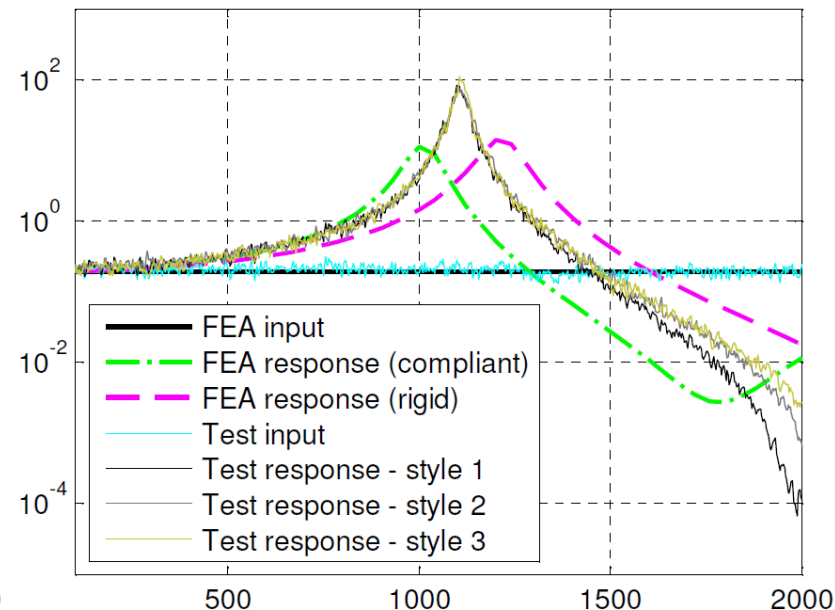
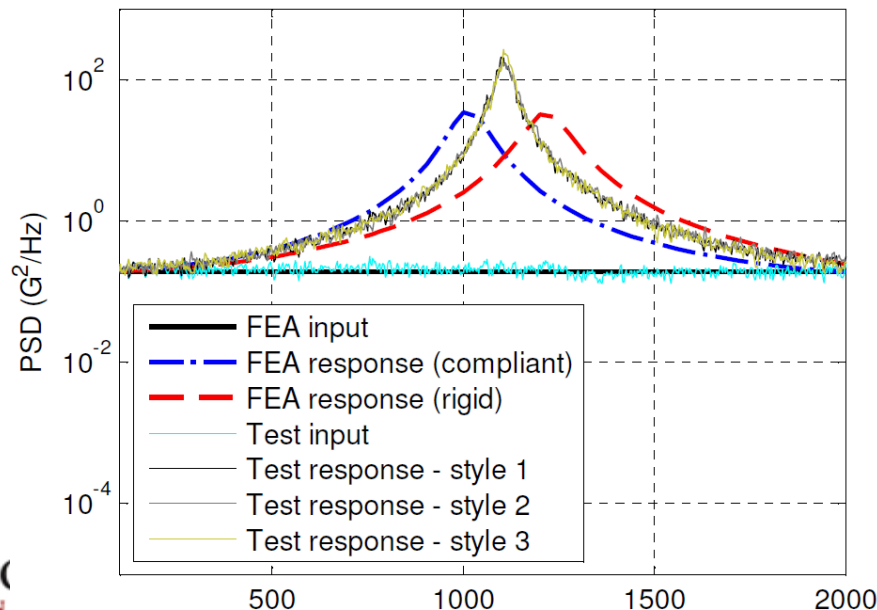
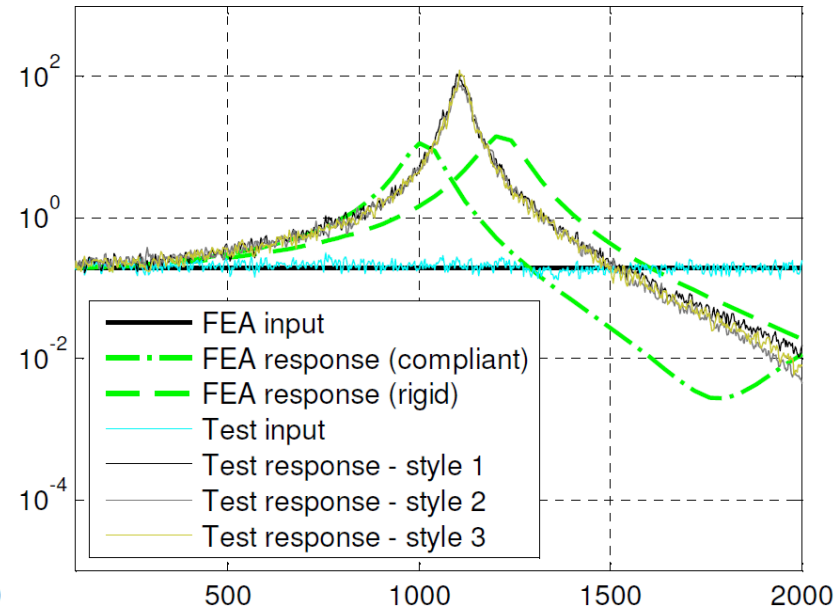
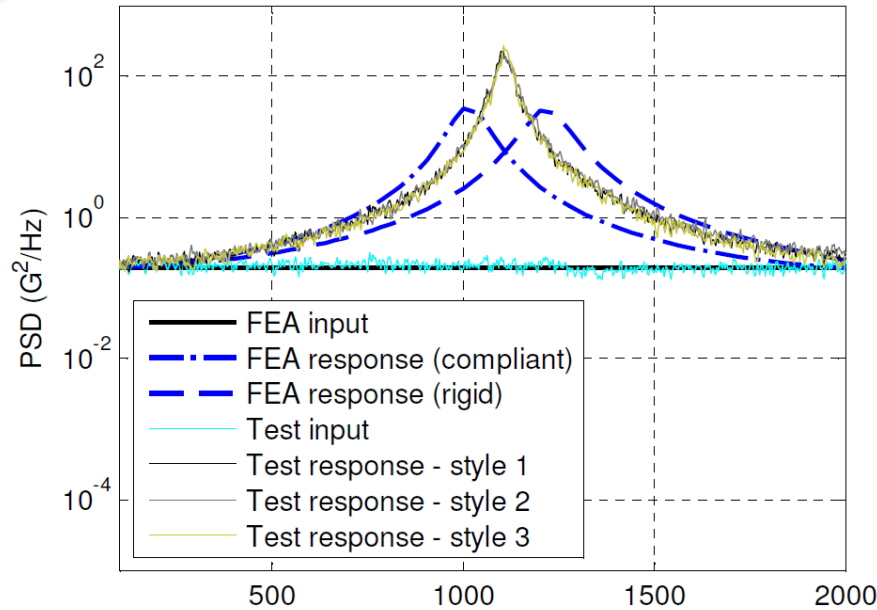
# Clamped, 40 pin, top board, center



# Clamped, 20 pin

*Center location*

*Midspan location*



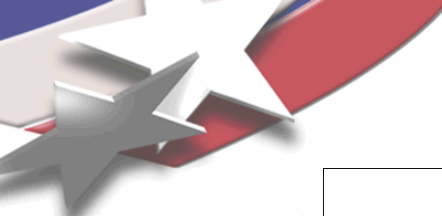
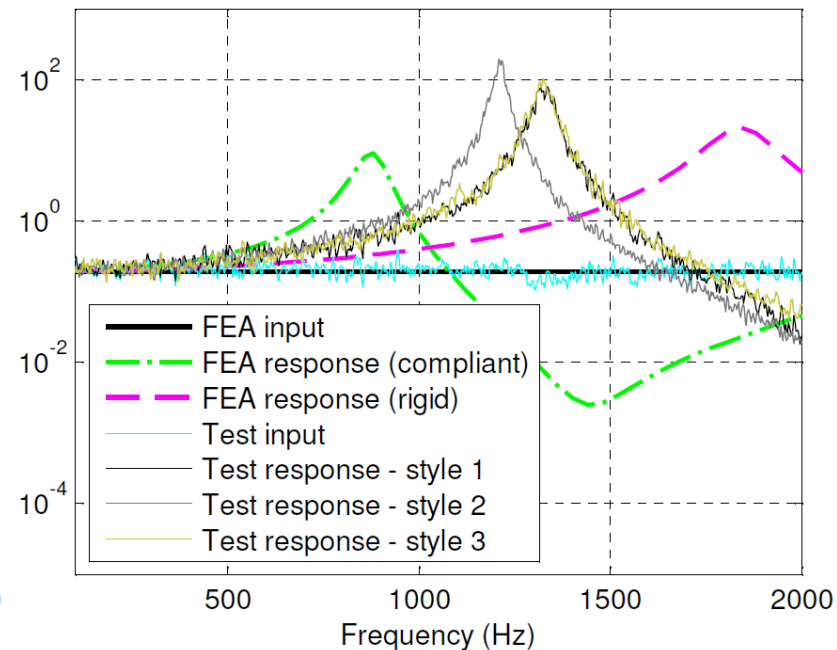
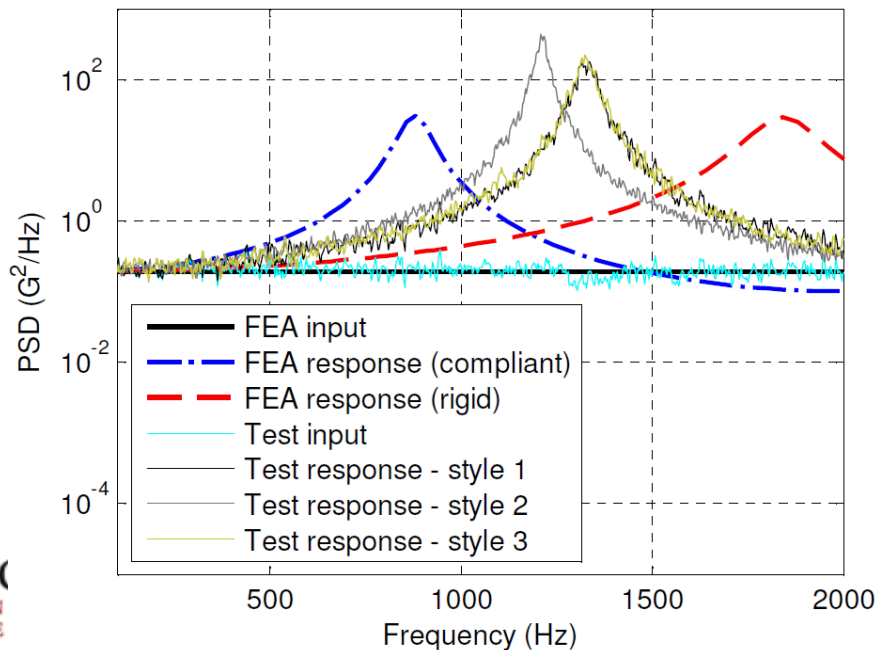
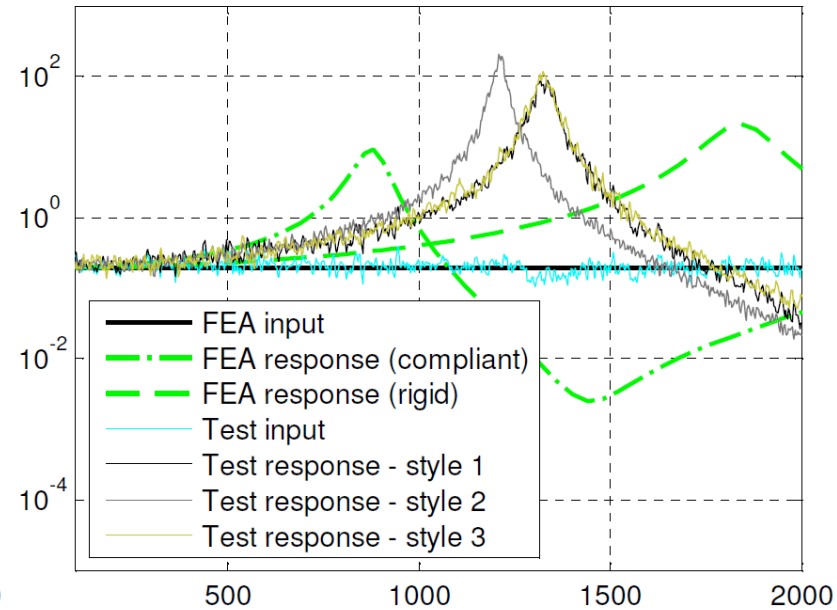
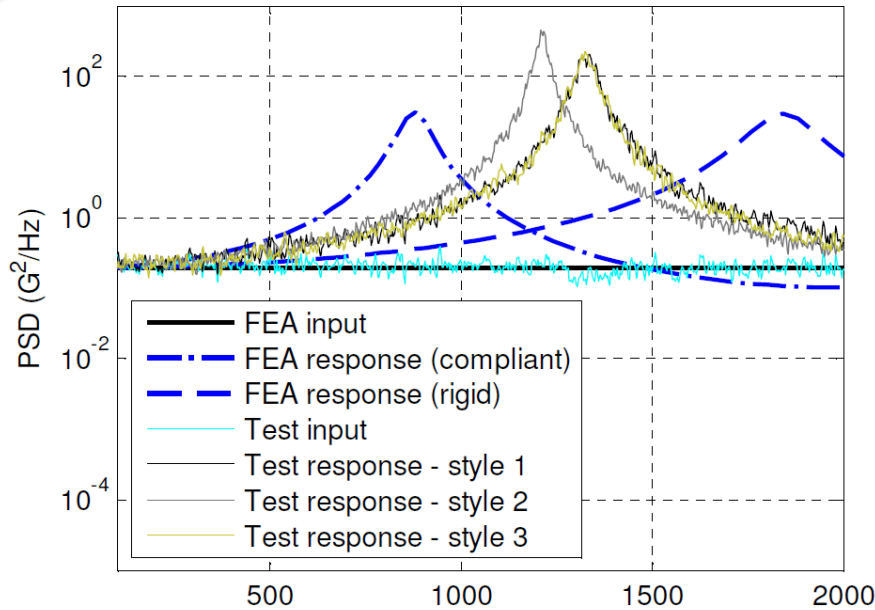
*Top  
circuit  
board*

*Bottom  
circuit  
board*

# Clamped, 40 pin

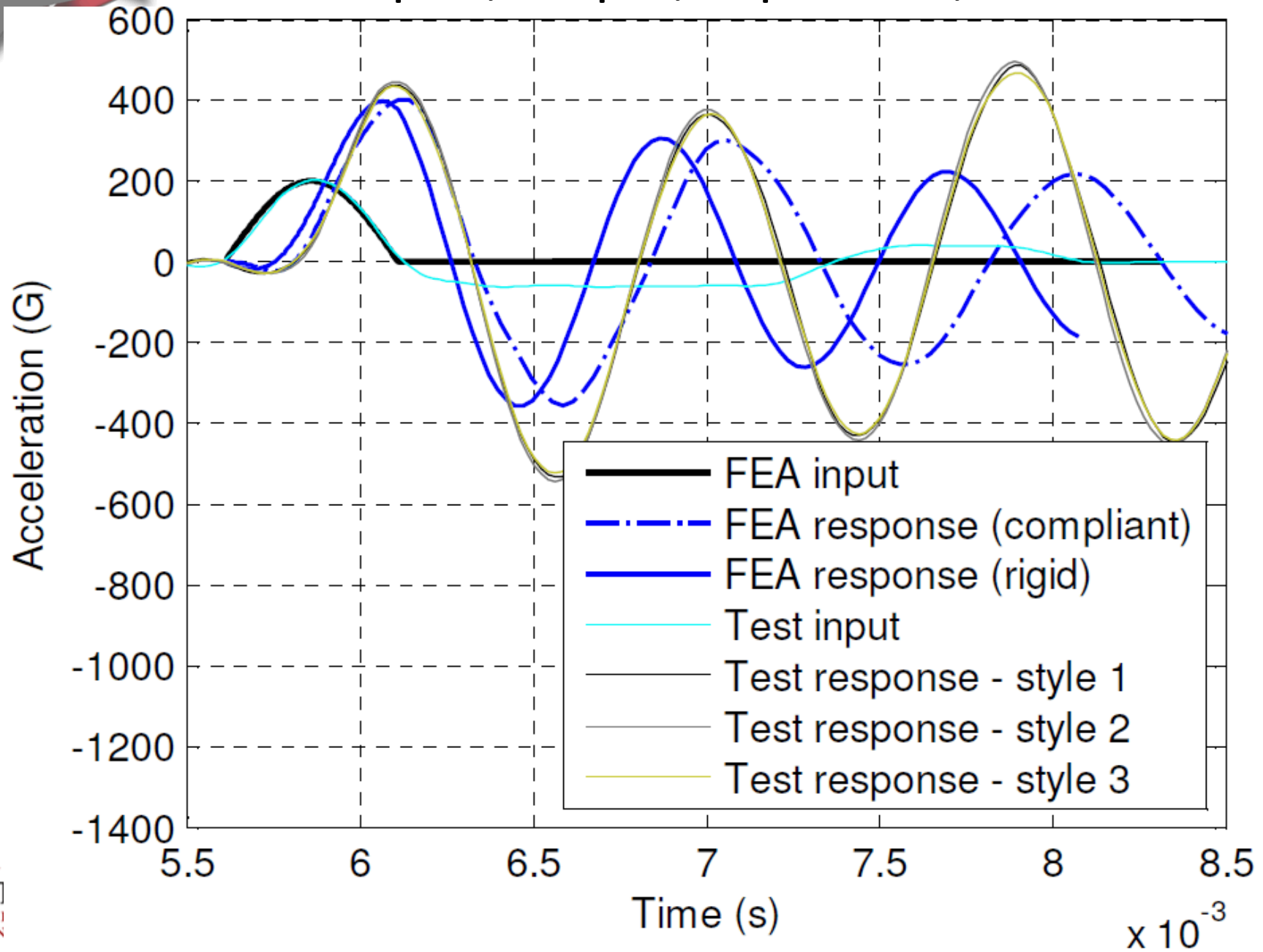
*Center location*

*Midspan location*

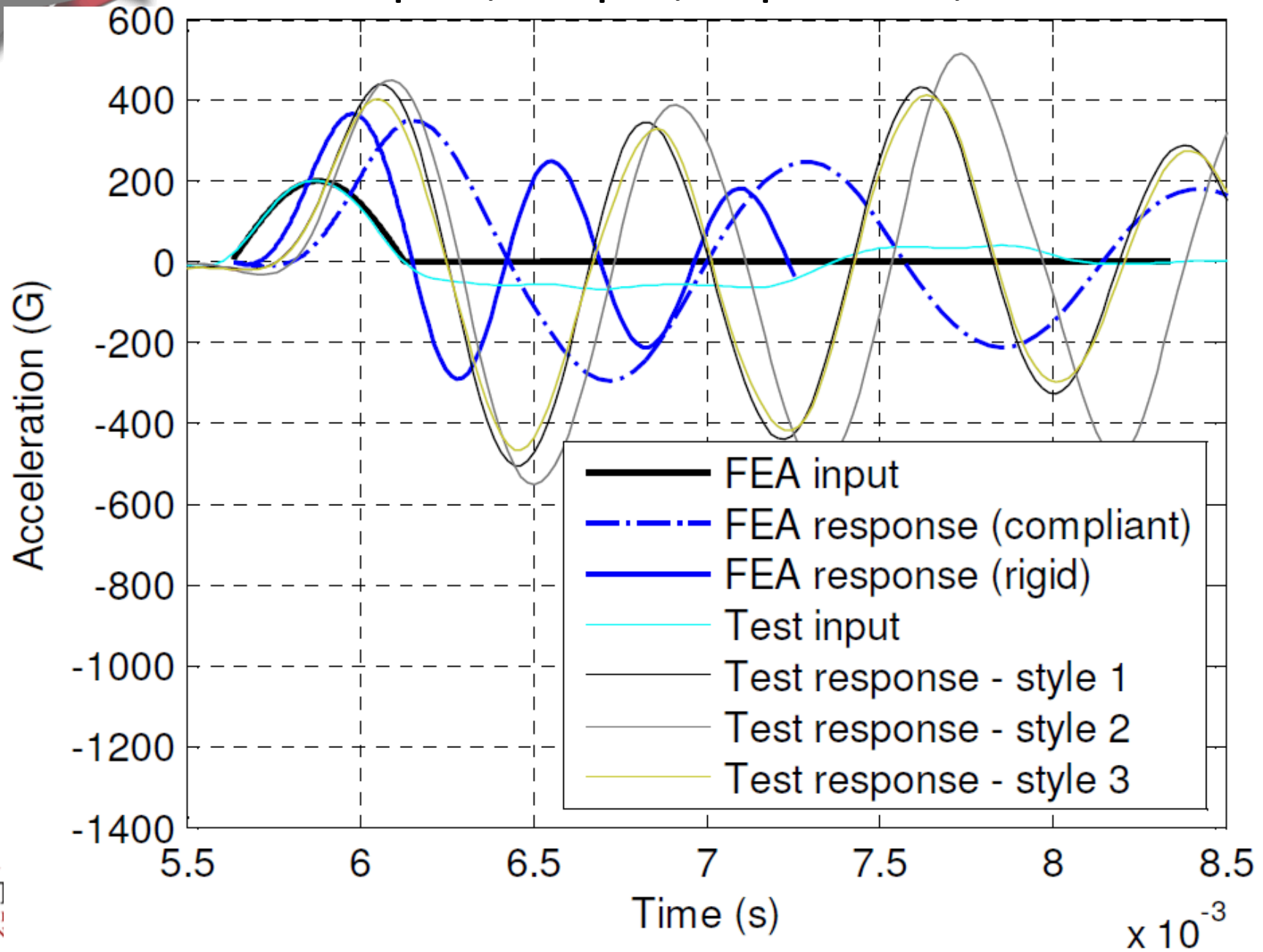


**Bottom  
circuit  
board**

# Clamped, 20 pin, top board, center



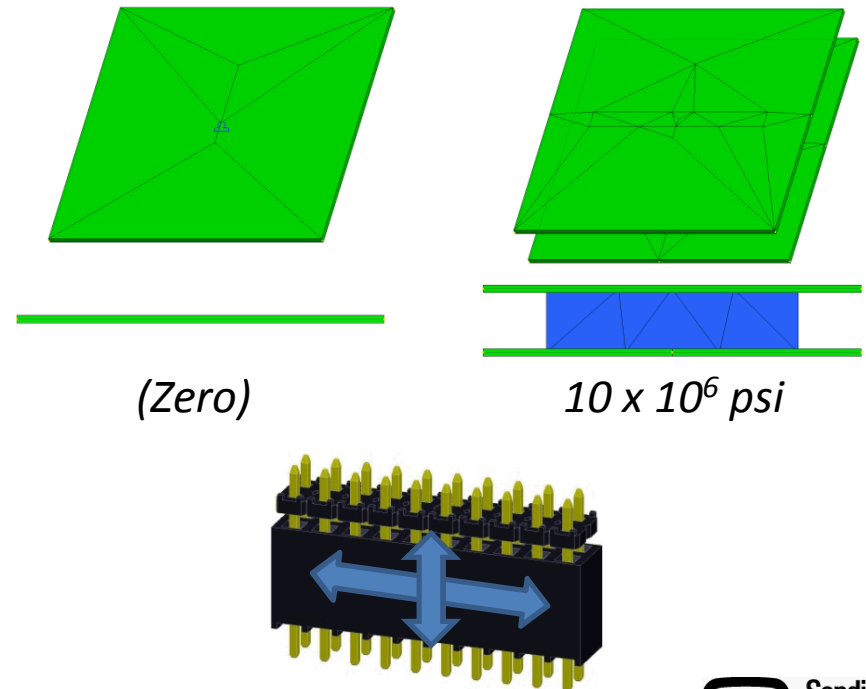
# Clamped, 40 pin, top board, center



# Preliminary conclusions

- Shape of predicted responses
  - Qualitatively correct
- 1<sup>st</sup> natural frequency
  - Well-bounded for 20 pin connectors
  - FEA predictions varied significantly for 30 and 40 pin connectors
- Response amplitude
  - Too low in all cases
  - Decrease damping to  $\sim 3\%$

- Connector 'stiffness'
  - Did not distinguish between bending stiffness and engagement 'stiffness'





# Proposed future work

- Bending vs. engagement stiffness
  - FEA models of connectors and/or 3-point bend tests
  - Validate with test data
- Explore other element types
  - Link, linear spring, or linear spring-damper (engagement 'stiffness')
  - Beam (bending stiffness)
  - Non-linear spring elements
  - Contact elements
- Abaqus (H-element code)
- Expand study to include 2<sup>nd</sup> and 3<sup>rd</sup> natural frequencies
- Possible outcomes
  - Validated modeling techniques
  - Implementation in model of multi-board telemetry system
  - Generalized recommendations based on key design parameters, e.g. board size, connector size, estimated material properties
- Goals
  - 1<sup>st</sup> natural freq.:  $\pm 5\%$
  - Peak response:  $\pm 10\%$
  - Total run time:  $\leq \sim 3$  hours
  - Enable efficient FEA modeling for conceptual design studies



# Summary

- Design of electronics packaging
  - Circuit board geometry ↔ dynamic response
- Case study (single board)
  - Research motivation: designs with multiple circuit boards
- Literature
  - Mechanical coupling at circuit board connectors not addressed
- Experimental test setup
  - Collected response data using 2 circuit boards with connector under a variety of conditions for FE model validation
- Preliminary FE analyses
  - Bounded estimate of response using ‘compliant’ and ‘rigid’ models
- Comparison of results
  - Good agreement between FEA and experimental results
- Preliminary conclusions
  - Effect of engagement ‘stiffness’ vs. bending stiffness remains unclear
- Proposed future work
  - Develop improved models to better match data
  - Develop guidelines for implementation in analyses of conceptual designs
- Questions



# Backups



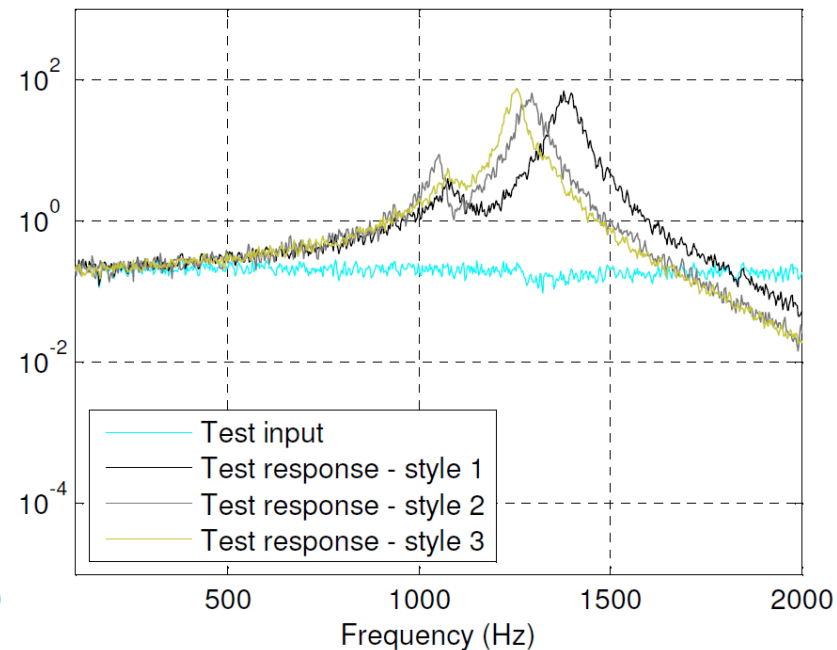
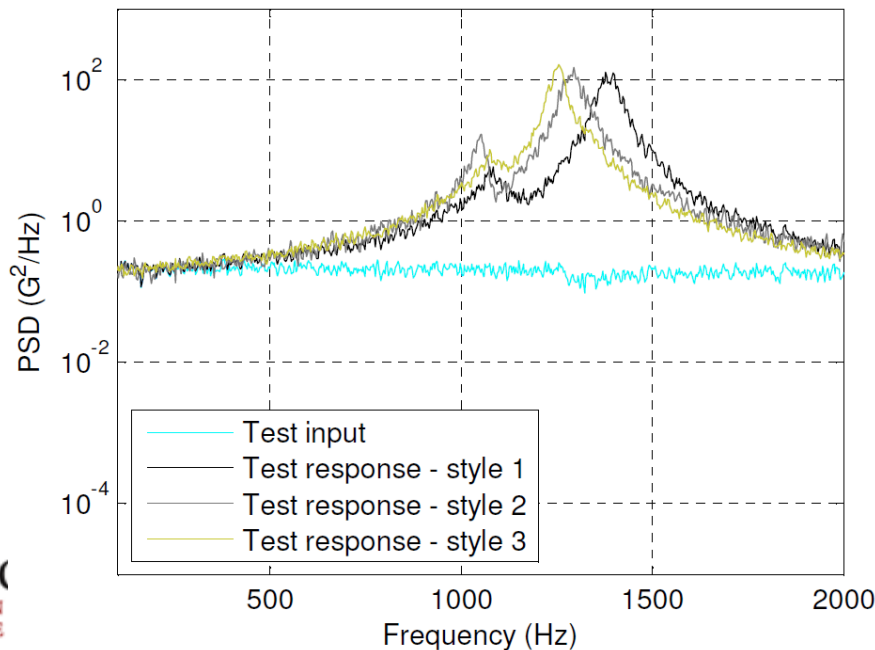
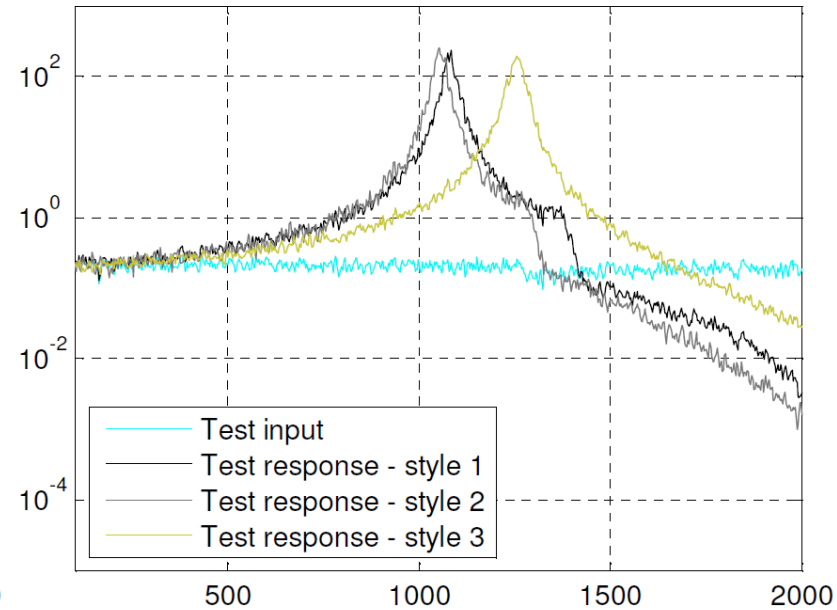
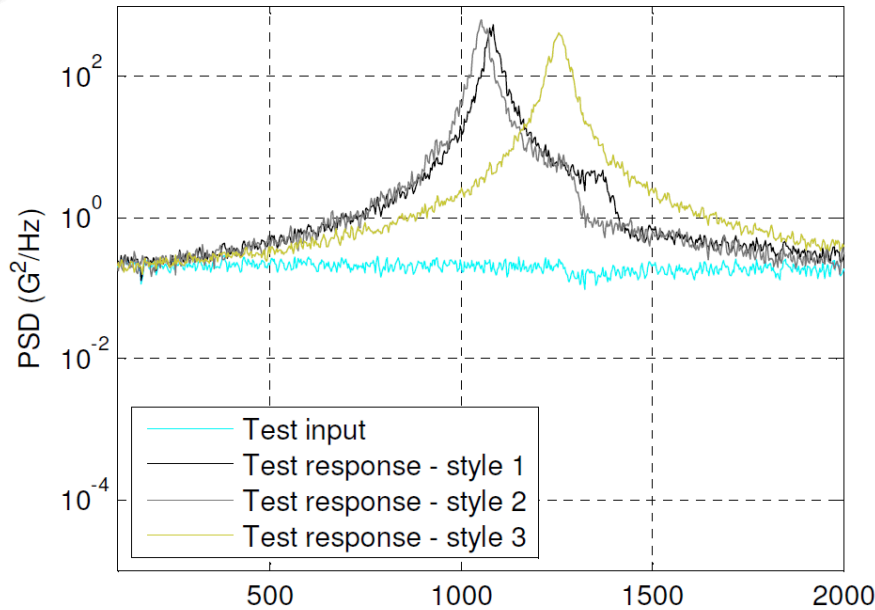
# References

1. Park, S., Shah, C., Kwak, J., Jang, C., Pitarresi, J., Park, T., and Jang, S., 2007, "Transient dynamic simulation and full-field test validation for a slim-PCB of mobile phone under drop / impact," *Proc. 57th Electronic Components and Technology Conference (ECTC)*, IEEE, New York.
2. Pitarresi, J., Roggeman, B., Chaparala, S., and Geng, P., 2004, "Mechanical shock testing and modeling of PC motherboards," *Proc. 54<sup>th</sup> Electronic Components and Technology Conference*, **1**, IEEE, New York, pp. 1047-1054.
3. Wu, R. R. Z., Radons, S., Long, X., and Stevens, K. K., 2002, "Vibration analysis of medical devices with a calibrated FEA model," *Computers & Structures*, **80**(12), pp. 1081-1086.
4. Lee, Y. C., Wang, B. T., Lai, Y. S., Yeh, C. L., and Chen, R. S., 2008, "Finite element model verification for packaged printed circuit board by experimental modal analysis," *Microelectronics Reliability*, **48**(11-12), pp. 1837-1846.
5. Donders, S., Takahashi, Y., Hadjit, R., Van Langenhove, T., Brughmans, M., Van Genechten, B., and Desmet, W., 2009, "A reduced beam and joint concept modeling approach to optimize global vehicle body dynamics," *Finite Elements in Analysis and Design*, **45**(6-7), pp. 439-455.
6. Mundo, D., Hadjit, R., Donders, S., Brughmans, M., and Desmet, W., 2009, "Simplified modeling of joints and beam-like structures for BIW optimization in a concept phase of the vehicle design process," *Finite Elements in Analysis and Design*, **45**(6-7), pp. 456-462.
7. Flowers, G. T., Xie, F., Bozack, M. J., and Malucci, R. D., 2004, "Vibration thresholds for fretting corrosion in electrical connectors," *IEEE Trans. Components and Packaging Technologies*, **27**(1), pp. 65-71.
8. Van Dijk, P., and Van Meijl, F., 1996, "Contact problems due to fretting and their solutions," *AMP J. of Technology*, **5**, pp. 14-18.

# Clamped, 40 pin, disengaged

*Center location*

*Midspan location*

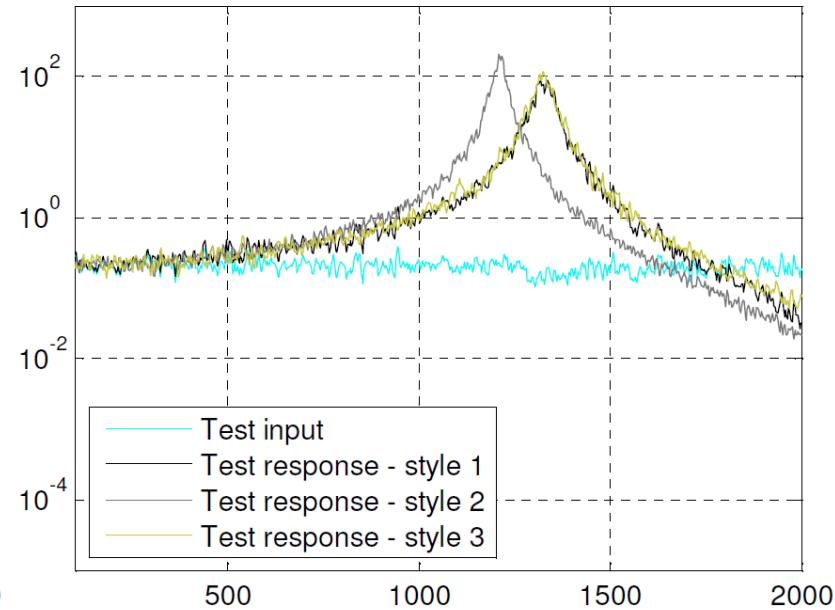
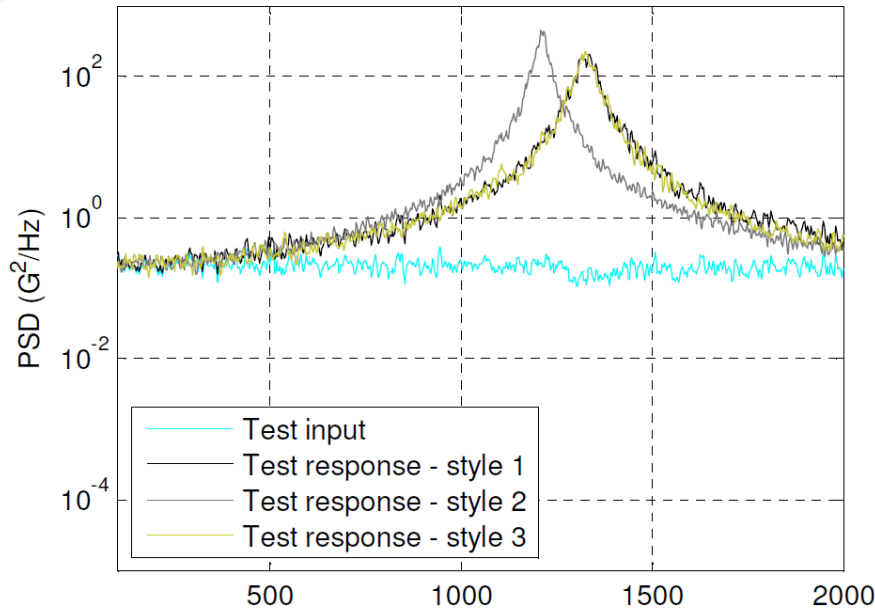


# Clamped, 40 pin, engaged

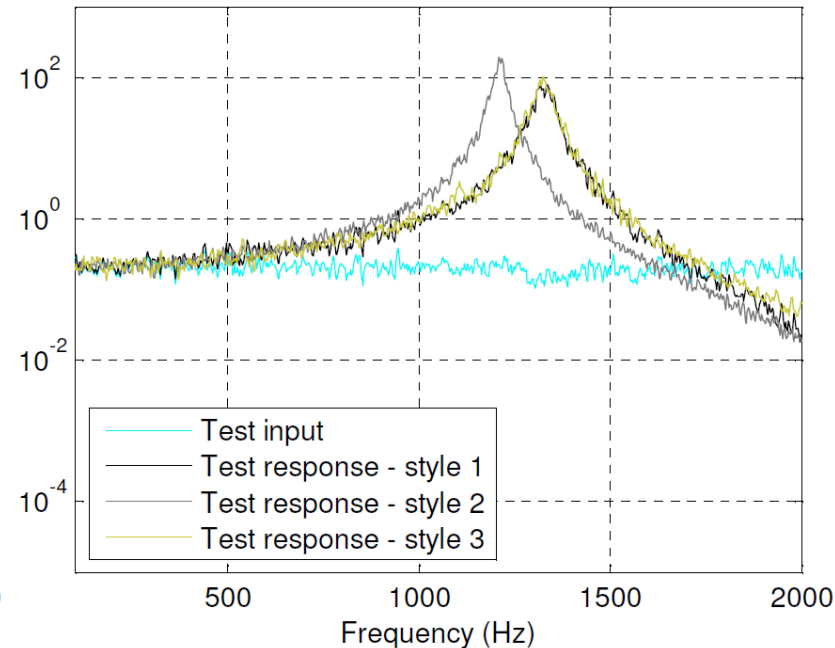
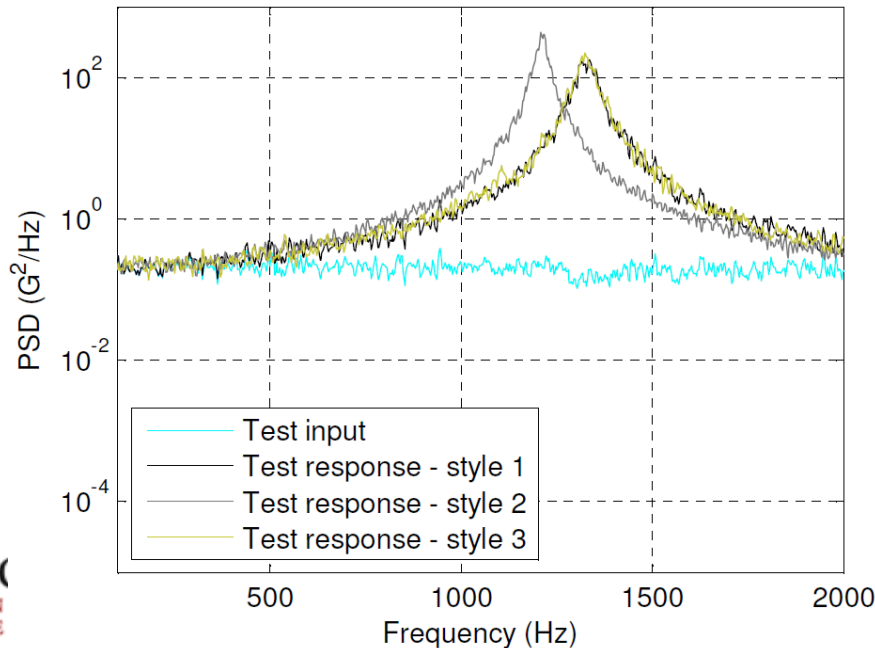
*Center location*

*Midspan location*

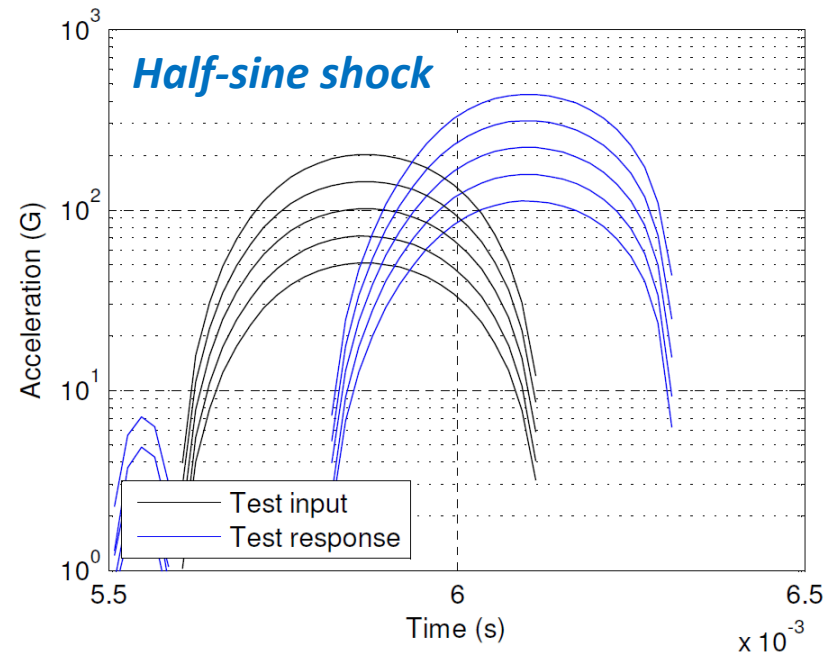
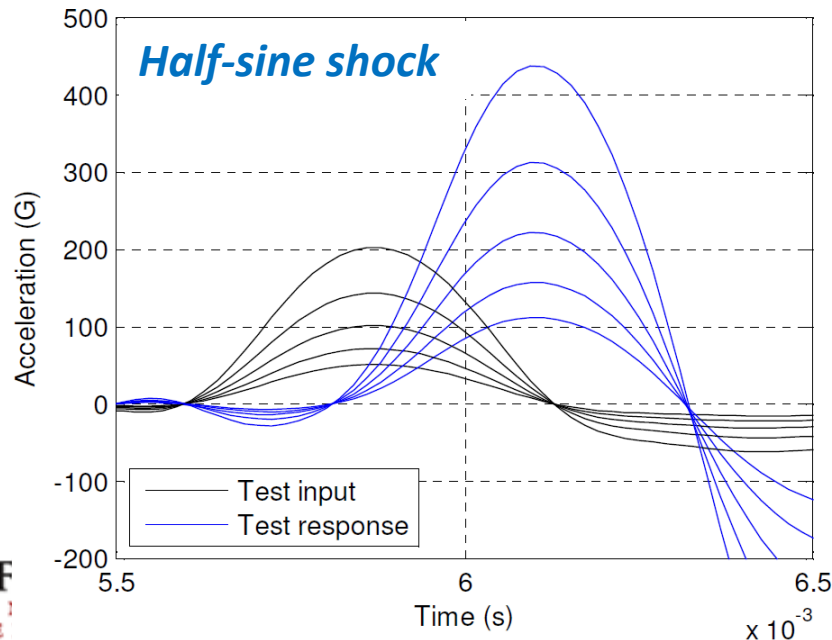
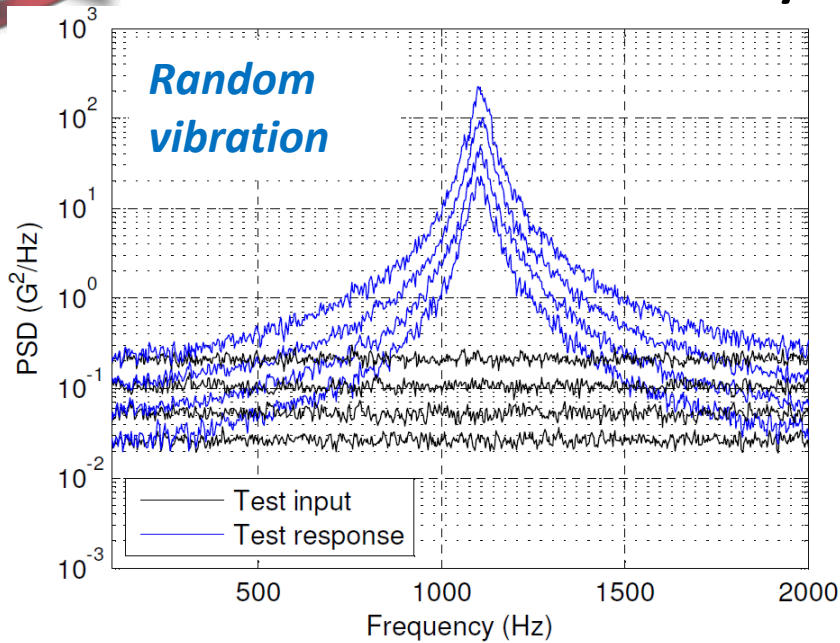
*Top  
circuit  
board*



*Bottom  
circuit  
board*



# Linearity of response



# Modal frequencies

Boundary condition	No. pins	Mechanical coupling	Mode		
			1 <sup>st</sup>	2 <sup>nd</sup>	3 <sup>rd</sup>
Clamped	20	None	1015	2483	2725
		Rigid	1217	3312	3443
	40	None	878	2477	2719
		Rigid	1845	3341	3497
Standoffs	20	None	810	1771	1849
		Rigid	1142	2754	2785
	40	None	718	1771	1849
		Rigid	1737	2910	2961



# Material properties of FR4

- Approximate values (taken from literature) are often adequate for typical design studies
  - $E = 2.0 \text{ to } 3.3 \times 10^6 \text{ psi}$
  - $\nu = 0.12 \text{ to } 0.25$
- Used for preliminary analyses
  - $E = 2.7 \times 10^6 \text{ psi}$
  - $\nu = 0.12$
- Higher accuracy required for developing board-to-board connector modeling techniques
- Tensile tests presently being performed to determine  $E$ ,  $\nu$ 
  - $E =$
  - $\nu =$